

NPN Silicon RF Transistor*

- For ESD protected high gain low noise amplifier
- Excellent ESD performance typical value 1000 V (HBM)
- Outstanding G_{ms} = 20 dB
 Noise Figure F = 0.9 dB
- SIEGET ® 45 Line
- Pb-free (ROHS compliant) package¹⁾
- Qualified according AEC Q101
- * Short term description





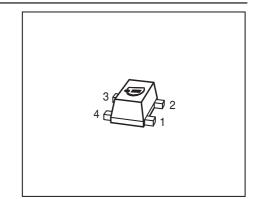
ESD (Electrostatic discharge) sensitive device, observe handling precaution!

Туре	Marking	Pin Configuration					Package	
BFP540FESD	AUs	1=B	2=E	3=C	4=E	-	-	TSFP-4

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{\sf CEO}$		V
$T_{A} > 0$ °C		4.5	
$T_{A} \le 0$ °C		4	
Collector-emitter voltage	V _{CES}	10	
Collector-base voltage	V_{CBO}	10	
Emitter-base voltage	V_{EBO}	1	
Collector current	I _C	80	mA
Base current	I _B	8	
Total power dissipation ²⁾	P _{tot}	250	mW
<i>T</i> _S ≤ 80 °C			
Junction temperature	T_{i}	150	°C
Ambient temperature	T_{A}	-65 150	
Storage temperature	T _{stq}	-65 150	

¹Pb-containing package may be available upon special request



 $^{^2 \}ensuremath{\textit{T}_S}$ is measured on the collector lead at the soldering point to the pcb





Thermal Resistance

Parameter	Symbol	Value	Unit
Junction - soldering point ¹⁾	R_{thJS}	≤ 280	K/W

Electrical Characteristics at $T_A = 25$ °C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
DC Characteristics					
Collector-emitter breakdown voltage	$V_{(BR)CEO}$	4.5	5	-	V
$I_{\rm C} = 1 \text{ mA}, I_{\rm B} = 0$					
Collector-emitter cutoff current	I _{CES}	-	-	10	μA
$V_{CE} = 10 \text{ V}, V_{BE} = 0$					
Collector-base cutoff current	I _{CBO}	-	-	100	nA
$V_{\rm CB} = 5 \text{ V}, I_{\rm E} = 0$					
Emitter-base cutoff current	I _{EBO}	-	-	10	μΑ
$V_{\rm EB} = 0.5 \rm V, \it I_{\rm C} = 0$					
DC current gain	h _{FE}	50	110	170	-
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 3.5 V, pulse measured					

 $^{^{1}\}mbox{For calculation of}\,R_{\mbox{\scriptsize thJA}}$ please refer to Application Note Thermal Resistance





Electrical Characteristics at $T_A = 25$ °C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
AC Characteristics (verified by random sampling	g)		,	ı	
Transition frequency	f_{T}	21	30	-	GHz
$I_{\rm C}$ = 50 mA, $V_{\rm CE}$ = 4 V, f = 1 GHz					
Collector-base capacitance	C _{cb}	-	0.16	0.26	pF
$V_{\text{CB}} = 2 \text{ V}, f = 1 \text{ MHz}, V_{\text{BE}} = 0 ,$					
emitter grounded					
Collector emitter capacitance	C _{ce}	-	0.4	-	
$V_{CE} = 2 \text{ V}, f = 1 \text{ MHz}, V_{BE} = 0$,					
base grounded					
Emitter-base capacitance	C_{eb}	-	0.55	-	
$V_{\text{EB}} = 0.5 \text{ V}, f = 1 \text{ MHz}, V_{\text{CB}} = 0$,					
collector grounded					
Noise figure	F				dB
$I_{\rm C}$ = 5 mA, $V_{\rm CE}$ = 2 V, f = 1.8 GHz, $Z_{\rm S}$ = $Z_{\rm Sopt}$		-	0.9	1.4	
$I_{\rm C}$ = 5 mA, $V_{\rm CE}$ = 2 V, f = 3 GHz, $Z_{\rm S}$ = $Z_{\rm Sopt}$		-	1.3	-	
Power gain, maximum stable ¹⁾	G _{ms}	-	20	-	dB
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm Sopt}$,					
$Z_{L} = Z_{Lopt}$, $f = 1.8 \text{ GHz}$					
Power gain, maximum available ¹⁾	G _{ma}	-	14.5	-	dB
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm Sopt}$,					
$Z_{L} = Z_{Lopt}, f = 3 \text{ GHz}$					
Transducer gain	S _{21e} ²				dB
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω , f = 1.8GHz		15.5	18	-	
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω , f = 3GHz		-	13	-	
Third order intercept point at output ²⁾	IP ₃	-	24.5	-	dBn
$V_{\text{CE}} = 2 \text{ V}, I_{\text{C}} = 20 \text{ mA}, Z_{\text{S}} = Z_{\text{L}} = 50\Omega, f = 1.8 \text{GHz}$					
1dB Compression point at output	P _{-1dB}	-	11	-	
$I_{\rm C}$ = 20 mA, $V_{\rm CE}$ = 2 V, $Z_{\rm S}$ = $Z_{\rm L}$ = 50 Ω , f = 1.8GHz				1	

 $^{{}^{1}}G_{ma} = |S_{21e} / S_{12e}| (k-(k^{2}-1)^{1/2}), G_{ms} = |S_{21e} / S_{12e}|$

²IP3 value depends on termination of all intermodulation frequency components.

Termination used for this measurement is 50 Ω from 0.1 MHz to 6 GHz



SPICE Parameter

For the SPICE model as well as for S-parameters (including noise parameters) please refer to our internet website www.infineon.com/rf.model.

Please consult our website and download the latest versions before actually starting your design.

You find the BFP540FESD SPICE model in the internet in MWO- and ADS- tools very quickly and conveniently.

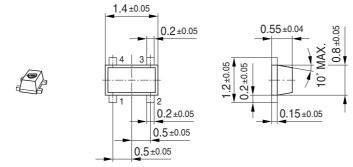
The simulation data have been generated and verified using typical devices.

The BFP540FESD SPICE model reflects the typical DC- and RF-performance with high accuracy.

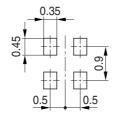
The SPICE model of BFP540FESD will be available in Q02 / 2010.



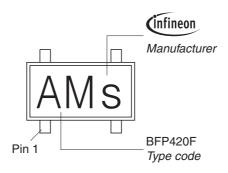
Package Outline



Foot Print

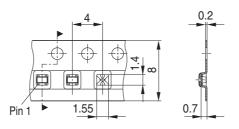


Marking Layout (Example)



Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel Reel ø330 mm = 10.000 Pieces/Reel





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